

## HL 57: Nitrides IV – Optical properties

Time: Friday 11:30–12:45

Location: POT/0051

HL 57.1 Fri 11:30 POT/0051

**Optical Properties of Sn-doped n-type GaN** — •HANNAH BENDIN<sup>1</sup>, ELIAS KLUTH<sup>1</sup>, KAZUKI OHNISHI<sup>2</sup>, KANSUKE HAMASAKI<sup>2</sup>, SHUGO NITTA<sup>2</sup>, NAOKI FUJIMOTO<sup>2</sup>, HIROTAKA WATANABE<sup>2</sup>, YOSHIO HONDA<sup>2</sup>, HIROSHI AMANO<sup>2</sup>, RÜDIGER GOLDHAHN<sup>1</sup>, and MARTIN FENEBERG<sup>1</sup> — <sup>1</sup>Otto-von-Guericke-Universität Magdeburg, Germany — <sup>2</sup>Nagoya University, Japan

GaN is at the heart of many contemporary electronic and optoelectronic applications. To increase the efficiency of high-power devices, the preparation of degenerately doped n-type GaN of high quality is required. Generally, Si and Ge are introduced as dopants, each giving rise to their own challenges. For example, high Si-doping is counteracted by carrier compensation and an increase in tensile stress. Recently, Sn has also gained interest as a dopant in GaN. Initial theoretical and experimental studies show promising results, introducing Sn as a candidate for strain control in n-type GaN via co-doping with Si or Ge, as the radius mismatch between Ga and Sn causes compressive strain, unlike Si or Ge. Here, we investigate Sn-doped samples with different carrier concentrations grown by halide vapor phase epitaxy by employing a variety of optical techniques. To determine the influence of the carrier concentration in GaN:Sn on the optical properties, we apply spectroscopic ellipsometry, Raman spectroscopy, and photoluminescence. Two sets of samples have been investigated: (I) GaN:Sn on a GaN/sapphire template and (II) GaN:Sn on a freestanding GaN substrate.

HL 57.2 Fri 11:45 POT/0051

**Optical properties of ScAlN: investigation by spectroscopic ellipsometry** — •CHRISTINA HARMS<sup>1</sup>, JONA GRÜMBEL<sup>1</sup>, DUC V. DINH<sup>2</sup>, ZHUOHUI CHEN<sup>3</sup>, OLIVER BRANDT<sup>2</sup>, MARTIN FENEBERG<sup>1</sup>, and RÜDIGER GOLDHAHN<sup>1</sup> — <sup>1</sup>Otto-von-Guericke-Universität, Institut für Physik, Magdeburg, Germany — <sup>2</sup>Paul-Drude-Institut für Festkörperelektronik, Leibniz-Institut im Forschungsverbund Berlin e.V., Berlin, Germany — <sup>3</sup>Huawei Technologies Canada Co., Ltd., Kanata, Canada

$\text{Sc}_x\text{Al}_{1-x}\text{N}$  alloys are of increasing interest due to their unique ferroelectric and optoelectronic properties. In this work, we investigate the dielectric function of this material using spectroscopic ellipsometry. A series of  $\text{Sc}_x\text{Al}_{1-x}\text{N}$  samples with  $0 \leq x \leq 0.35$ , grown on AlN/Si by plasma-assisted molecular beam epitaxy, were measured in the infrared (IR) and ultraviolet (UV) spectral range. In the IR range, the  $E_1(\text{TO})$  phonon mode is characterized in terms of its resonance frequency  $\omega$  and broadening  $\gamma$ , which are analyzed as a function of Sc content. Additionally, the dielectric limit  $\varepsilon_\infty$  is derived. With increasing Sc content,  $\omega$  decreases, while both  $\gamma$  and  $\varepsilon_\infty$  increase. In the UV range, we determine the optical bandgap  $E_g$  as well as the corresponding  $\varepsilon_\infty$  and describe the observed trends across the composition range. Here,  $E_g$  decreases systematically with increasing Sc content and  $\varepsilon_\infty$  increases accordingly. The results are compared with recent results from literature, showing consistent trends in the optical properties throughout the investigated composition range.

HL 57.3 Fri 12:00 POT/0051

**Near-lattice-matched AlScN/GaN heterostructures studied by spectroscopic ellipsometry and photoluminescence** — •ALWIN WÜTHRICH<sup>1</sup>, RAJENDRA KUMAR<sup>2</sup>, OANA MALIS<sup>2</sup>, RÜDIGER GOLDHAHN<sup>1</sup>, and MARTIN FENEBERG<sup>1</sup> — <sup>1</sup>Institut für Physik, Otto-von-Guericke-Universität Magdeburg, Germany — <sup>2</sup>Department of

Physics and Astronomy, Purdue University, USA

Understanding the fundamental properties of the novel ferroelectric material AlScN, such as ferroelectricity, tunable lattice constants, a wide and tunable band gap, and high piezoelectric coefficients, is crucial for its correct implementation in modern applications. Examples include processing units based on non-volatile memory and the design of infrared devices that utilize transitions between strongly confined electronic states, i.e., intersubband transitions. Here, near-lattice-matched AlScN layers (with 4–25% Sc) were grown by molecular beam epitaxy (MBE) on MBE-grown GaN layers. The samples were investigated by spectroscopic ellipsometry from the near-infrared to the far-ultraviolet range, probing infrared-active phonons and interband transitions. Additionally, the samples were studied by temperature-dependent photoluminescence, revealing luminescence from a two-dimensional electron gas.

HL 57.4 Fri 12:15 POT/0051

**Near-Infrared Photocurrent Spectroscopy of InN Two-Terminal Devices** — •ALEXANDRA V. NEMMAIER<sup>1,2</sup>, MAXIMILIAN A. GRUBER<sup>1,2</sup>, ABHILASH ULHE<sup>1,2</sup>, GREGOR KOBLMÜLLER<sup>1,2</sup>, and ALEXANDER W. HOLLEITNER<sup>1,2</sup> — <sup>1</sup>Walter Schottky Institute, TU Munich, Germany — <sup>2</sup>Exzellenzcluster e-conversion, Munich, Germany

The semiconductor InN, with its narrow bandgap, high electron mobility, and specific carrier cooling mechanisms, is a promising platform for optoelectronics and hot carrier solar cells. We investigate epitaxial InN layers grown on GaN by near-infrared photocurrent spectroscopy. We measure the spatially resolved photocurrent to characterize the photoresponse in gated two-terminal devices. This approach offers a new perspective on hot carrier generation, charge carrier transport, and relaxation mechanisms close to the bandgap of the material.

HL 57.5 Fri 12:30 POT/0051

**Structural and vibrational properties of strain-free  $\text{Al}_{1-x}\text{Sc}_x\text{N}$  nanowires** — ADRIANO NOTARANGELO<sup>1</sup>, ILEANA FLOREA<sup>2</sup>, PHILIPPE VENNÉGUÈS<sup>2</sup>, AIDAN CAMPBELL<sup>1</sup>, HANS TORNATZKY<sup>1</sup>, JONAS LÄHNEMANN<sup>1</sup>, THOMAS AUZELLE<sup>1</sup>, LUTZ GEELHAAR<sup>1</sup>, OLIVER BRANDT<sup>1</sup>, and •PHILIPP JOHN<sup>1</sup> — <sup>1</sup>Paul-Drude-Institut für Festkörperelektronik, Leibniz-Institut im Forschungsverbund Berlin e.V. 10117 Berlin, Germany — <sup>2</sup>Université Côte d'Azur, CRHEA, CNRS, 06905 Sophia-Antipolis Cedex, France

The incorporation of Sc into the wurtzite crystal lattice of AlN enhances its piezoelectricity and induces ferroelectricity, making  $\text{Al}_{1-x}\text{Sc}_x\text{N}$  an attractive material for novel types of group-III nitride based devices. Yet, the lattice distortions giving rise to these functionalities are superimposed to distortions arising from residual strain introduced during the heteroepitaxy on lattice-mismatched substrates.

In this work, self-assembled wurtzite  $\text{Al}_{1-x}\text{Sc}_x\text{N}$  nanowires are grown by molecular beam epitaxy, varying the Sc content  $x$  from 0 to 0.38. The nanowire geometry allows elastic relaxation to occur, resulting in strain-free, bulk-like  $\text{Al}_{1-x}\text{Sc}_x\text{N}$ . A non-linear evolution of lattice parameters and a continuous red-shift of the  $E_2^{\text{high}}$  and  $A_1(\text{TO})$  phonon modes as a function of Sc content are found, confirming its incorporation into the wurtzite lattice and revealing modifications of anion-cation bond strength and coordination environment.

Our results highlight the advantages of bulk-like  $\text{Al}_{1-x}\text{Sc}_x\text{N}$  for probing its fundamental properties, laying the ground work for further device applications.